IN THE CLAIMS:

Please amend the claims as follows (bracketed portions are removed, and underlined portions are inserted):

11. (currently amended) A field distribution measuring method for measuring an electric field or a magnetic field [by a probe] comprising the following steps of:

measuring at a plurality of sampling points while continuously sweeping by a probe; [, wherein]

computing a shift amount of the sampling points [is computed,] based on a spurious spectrum generated by a displacement between a <u>first probe</u> position [of the probe and a measuring timing,] defined by a timing of a trigger signal and stored as position information of the probe and a second probe position defined by a timing of an actual measurement at the sampling point; and

measuring a distribution of the electric field or the magnetic field [is measured in consideration of] by calculating the second probe position based on the shift amount and the position information, and using the calculated second probe position as an actual position of the sampling point.

12. (currently amended) A field distribution measuring method according to claim 11, <u>further</u> comprising <u>the steps of</u>:

storing a plurality of measured data measured by the probe sweeping in a first direction together with <u>the</u> position information of the probe as reference data;

storing a plurality of measured data measured by the probe sweeping in a second direction opposite to the first direction together with the position information of the probe as adjustment data;

interpolating the adjustment data to compute interpolated data with data between the sampling points interpolated;

computing spatial frequency power spectra for the reference data and the interpolated data; and

computing the shift amount of the sampling points, based on the spatial frequency power spectra.

13. (original) A field distribution measuring method according to claim 12, wherein

the shift amount of the sampling points is computed based on an accumulated value of the spatial frequency power spectra.

14. (currently amended) A field distribution measuring method according to claim 13, wherein

the shift amount of the sampling points is judged, based on [a] an interpolation point where the accumulated value of the spatial frequency power spectra is below a prescribed value.

15. (currently amended) A field distribution measuring method according to claim 13, wherein

the shift amount of the sampling points is judged, based on [a] an interpolation point where the accumulated value of the spatial frequency power spectra is minimum.

16. (currently amended) A field distribution measuring method according to claim 14, wherein

the shift amount of the sampling points is judged, based on [a] an interpolation point where the accumulated value of the spatial frequency power spectra is minimum.

17. (currently amended) A field distribution measuring method according to claim 11, wherein

the shift [amount of the] amounts relating to the respective sampling points [is] are computed [in consideration of acceleration and deceleration of the probe] when a sweeping rate of the probe is not constant.

18. (currently amended) A field distribution measuring method according to claim 12, wherein

the shift [amount of the] amounts relating to the respective sampling points [is] are computed [in consideration of acceleration and deceleration of the probe] when a sweeping rate of the probe is not constant.

19. (original) A field distribution measuring method according to claim 11, wherein

the probe sweeps on a two-dimensional plane.

20. (original) A field distribution measuring method according to claim 12, wherein

the probe sweeps on a two-dimensional plane.

21. (currently amended) A field distribution measuring method according to claim 11, wherein

the probe [sweep] sweeps in a three-dimensional space.

22. (currently amended) A field distribution measuring method according to claim 12, wherein

the probe [sweep] sweeps in a three-dimensional space.

23. (currently amended) A field distribution measuring apparatus comprising:

a probe for detecting an electric field or a magnetic field at a plurality of sampling points while continuously sweeping on a plane or in a space;

 \underline{a} measuring unit for measuring the electric field or the magnetic field detected by the probe;

<u>a</u> storing unit for storing data of the electric field or the magnetic field measured by the measuring unit together with position data of the probe <u>defined</u> by a <u>timing</u> of a trigger signal;

<u>a</u> data processing unit for computing a shift amount of sampling points generated by a displacement between a <u>first</u> <u>probe</u> position [of the probe and a measuring timing, based on data] stored in the storing unit <u>as the position data of the</u>

probe and a second probe position defined by a timing of an actual measurement at the sampling point; and

a computing unit for computing a spatial distribution of the electric field or the magnetic field detected by the probe[, in consideration of the shift amount of the sampling points computed by the data processing unit] by calculating the second probe position based on the shift amount and the first probe position and using the calculated second position as an actual position of the sampling point.

24. (currently amended) A field distribution measuring apparatus according to claim 23, wherein

the data processing unit computes the shift amount of the sampling points, based on a spurious spectrum generated by the displacement between the [position of the probe and the measuring timing] first probe position and the second probe position.